

### NPN SILICON EPITAXIAL TRANSISTOR FOR HIGH-SPEED SWITCHING

The 2SC2517 is a mold power transistor developed for high-speed switching. This transistor is ideal for use in drivers such as switching regulators, DC/DC converters, high-frequency power amplifiers.

#### FEATURES

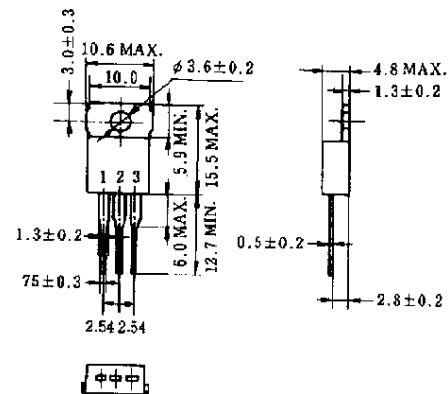
- Low collector saturation voltage:  
 $V_{CE(sat)} \leq 0.6 \text{ V}$  (at  $I_c = 3.0 \text{ A}$ )
- Fast switching speed:  
 $t_f \leq 0.5 \mu\text{s}$  (at  $I_c = 3.0 \text{ A}$ )
- Wide base reverse-bias SOA:  
 $V_{CEX(sus)} \leq 150 \text{ V}$  (at  $I_c = 3.0 \text{ A}$ )

#### ABSOLUTE MAXIMUM RATINGS ( $T_a = 25^\circ\text{C}$ )

Parameter	Symbol	Ratings	Unit
Collector to base voltage	$V_{CBO}$	150	V
Collector to emitter voltage	$V_{CEO}$	100	V
Emitter to base voltage	$V_{EBO}$	12	V
Collector current (DC)	$I_{C(DC)}$	5.0	A
Collector current (pulse)	$I_{C(pulse)^*}$	10	A
Base current (DC)	$I_{B(DC)}$	2.5	A
Total power dissipation	$P_T$ ( $T_c = 25^\circ\text{C}$ )	30	W
Total power dissipation	$P_T$ ( $T_a = 25^\circ\text{C}$ )	1.5	W
Junction temperature	$T_j$	150	$^\circ\text{C}$
Storage temperature	$T_{stg}$	-55 to +150	$^\circ\text{C}$

\*  $PW \leq 300 \mu\text{s}$ , duty cycle  $\leq 10\%$

#### PACKAGE DRAWING (UNIT: mm)



#### Electrode Connection

1. Base (B)
2. Collector (C)
3. Emitter (E)
4. Fin (collector)

EIAJ: SC-46  
JEDEC: TO-220AB  
IEC: —

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**ELECTRICAL CHARACTERISTICS (Ta = 25°C)**

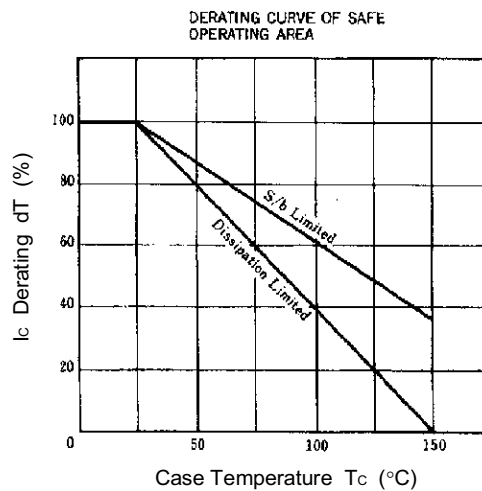
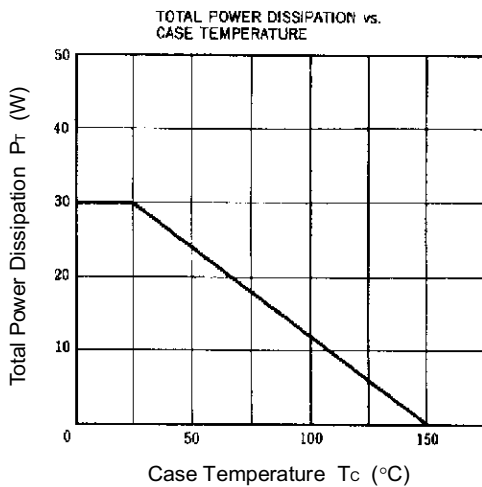
Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Collector to emitter voltage	V <sub>CEQ(SUS)</sub>	I <sub>C</sub> = 3.0 A, I <sub>B1</sub> = 0.3 A, L = 1 mH	100			V
Collector to emitter voltage	V <sub>CEX(SUS)1</sub>	I <sub>C</sub> = 3.0 A, I <sub>B1</sub> = -I <sub>B2</sub> = 0.3 A, V <sub>BE(OFF)</sub> = -5.0 V, L = 180 μH, clamped	150			V
Collector to emitter voltage	V <sub>CEX(SUS)2</sub>	I <sub>C</sub> = 6.0 A, I <sub>B1</sub> = 1.2 A, I <sub>B2</sub> = -0.3 A, V <sub>BE(OFF)</sub> = -5.0 V, L = 180 μH, clamped	100			V
Collector cutoff current	I <sub>CB0</sub>	V <sub>CB</sub> = 100 V, I <sub>E</sub> = 0			10	μA
Collector cutoff current	I <sub>CER</sub>	V <sub>CE</sub> = 100 V, R <sub>BE</sub> = 51 Ω, Ta = 125°C			1.0	mA
Collector cutoff current	I <sub>CX1</sub>	V <sub>CE</sub> = 100 V, V <sub>BE(OFF)</sub> = -1.5 V			10	μA
Collector cutoff current	I <sub>CX2</sub>	V <sub>CE</sub> = 100 V, V <sub>BE(OFF)</sub> = -1.5 V, Ta = 125°C			1.0	mA
Emitter cutoff current	I <sub>EB0</sub>	V <sub>EB</sub> = 10 V, I <sub>C</sub> = 0			10	μA
DC current gain	h <sub>FE1</sub>	V <sub>CE</sub> = 5.0 V, I <sub>C</sub> = 0.2 A*	40			
DC current gain	h <sub>FE2</sub>	V <sub>CE</sub> = 5.0 V, I <sub>C</sub> = 2.0 A*	40		200	
Collector saturation voltage	V <sub>CE(sat)</sub>	I <sub>C</sub> = 3.0 A, I <sub>B</sub> = 0.3 A*			0.6	V
Base saturation voltage	V <sub>BE(sat)</sub>	I <sub>C</sub> = 3.0 A, I <sub>B</sub> = 0.3 A*			1.5	V
Turn-on time	t <sub>on</sub>	I <sub>C</sub> = 3.0 A, R <sub>L</sub> = 17 Ω, I <sub>B1</sub> = -I <sub>B2</sub> = 0.3 A, V <sub>CC</sub> ≅ 50 V			0.5	μs
Storage time	t <sub>stg</sub>	Refer to the test circuit.			2.5	μs
Fall time	t <sub>f</sub>				0.5	μs

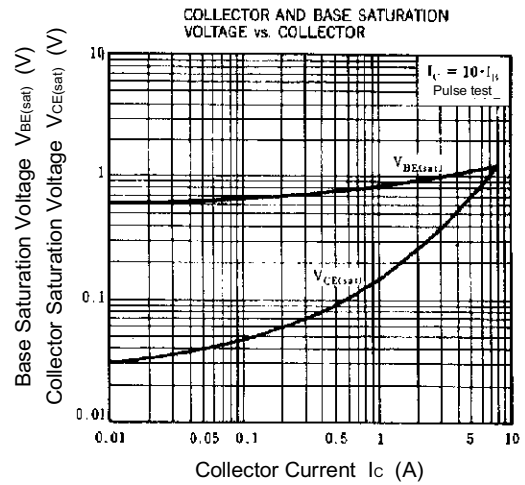
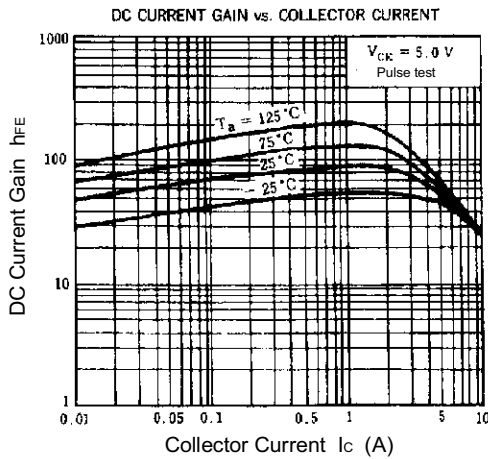
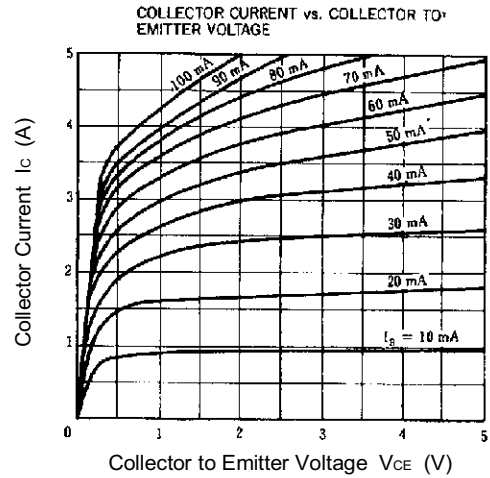
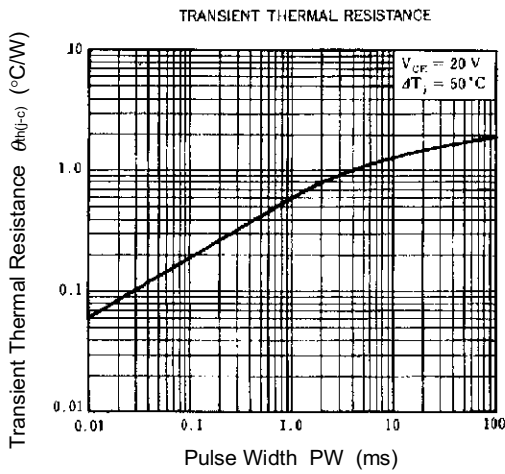
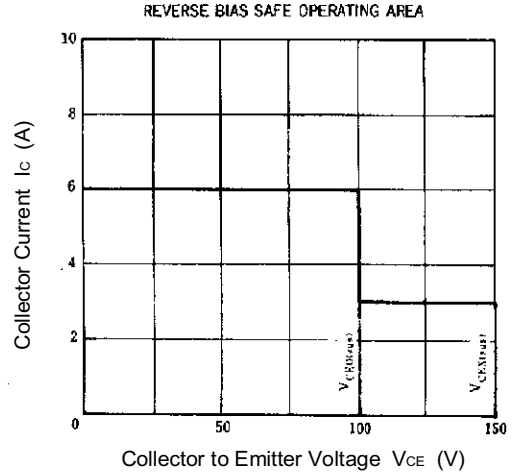
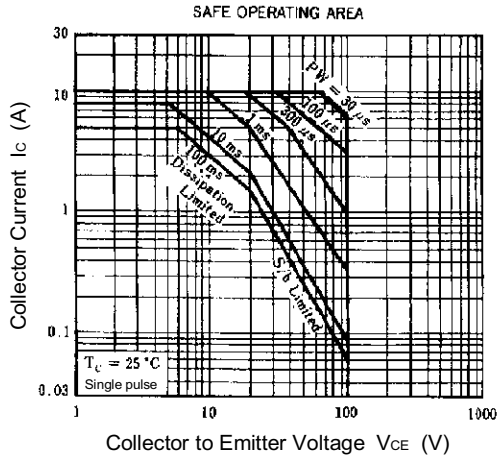
\* Pulse test PW ≤ 350 μs, duty cycle ≤ 2%

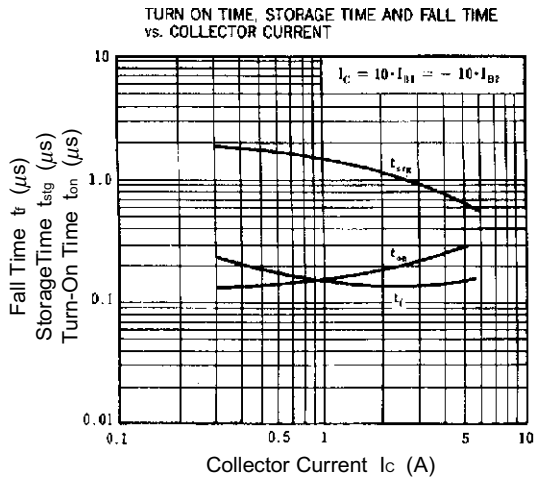
**h<sub>FE2</sub> CLASSIFICATION**

Marking	M	L	K
h <sub>FE2</sub>	40 to 80	60 to 120	100 to 200

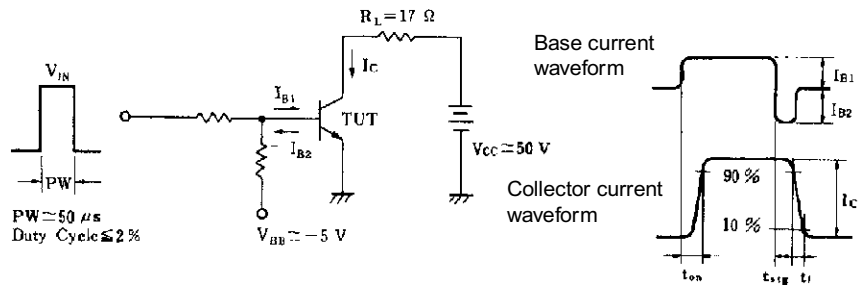
**TYPICAL CHARACTERISTICS (Ta = 25°C)**







SWITCHING TIME ( $t_{on}$ ,  $t_{stg}$ ,  $t_f$ ) TEST CIRCUIT



[MEMO]

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